

<b>Notice of References Cited</b>	Application/Control No. 10/810,164		Applicant(s)/Patent Under Reexamination WU ET AL.	
	Examiner Srirama Channavajjala		Art Unit 2166	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0056019	05-2002	Kolodner et al.	711/6
*	B	US-2002/0099765	07-2002	Otis, Allen J.	709/203
*	C	US-2003/0200392	10-2003	Wright et al.	711/118
*	D	US-2005/0273567	12-2005	Blandy, Geoffrey Owen	711/170
*	E	US-7,174,354	02-2007	Andreasson, Eva	707/206
*	F	US-6,865,657	03-2005	Traversat et al.	711/170
*	G	US-6,763,440	07-2004	Traversat et al.	711/159
*	H	US-6,598,141	07-2003	Dussud et al.	711/170
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02/23345	03-2002	PCT	Rodriguez Rivera,G et al.	12/00
	O	WO 99/64955	12-1999	PCT	Heller,Stever et al.	12/02
	P	WO 01/97042	12-2001	PCT	Fresko,Nedim et al.	12/02
	Q	UK 2349719	11-2000	GB	Hillel Kolodner et al.	12/02
	R	WO 2005/013134	02-2005	PCT	Gansha,Wu et al.	12/02
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Srisa-an W et al. "active memory processor: a hardware garbage collector for real-time Java embedded devices", Mobile computing, IEEE transactions, vol 2, issue: 2, 2003, pp 89-101
	V	Yamamoto,K et al. "distributed persistent object system with uniform representation of pointers and its garbage collection", proceedings of the twenty-ninth Hawaii international conference on system sciences, 1996, vol 1, pp 12-21
	W	Maheshwari,U et al. "fault-tolerant distributed garbage collection in a client-server object-oriented database", proceedings of the third international conference on parallel and distributed information systems, 1994, pp 239-248
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.